

Main Product Characteristics:

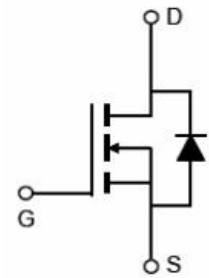
V_{DSS}	30V
$R_{DS(on)}$	4.2m Ω (Typ.)
I_D	100A



TO-252 (DPAK)



Marking and Pin Assignments



Schematic Diagram

Features and Benefits:

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature


Description:

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

Absolute Max Rating:

Symbol	Parameter	Max.	Units
$I_D @ T_C = 25^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10\text{V}$ ①	100	A
I_{DM}	Pulsed Drain Current ②	400	
$P_D @ T_C = 25^\circ\text{C}$	Power Dissipation ③	73	W
V_{DS}	Drain-Source Voltage	30	V
V_{GS}	Gate-to-Source Voltage	± 20	V
E_{AS}	Single Pulse Avalanche Energy @ $L=0.5\text{mH}$	137	mJ
I_{AS}	Avalanche Current	23	A
$T_J \quad T_{STG}$	Operating Junction and Storage Temperature Range	-55 to +150	$^\circ\text{C}$

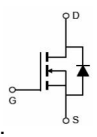
Thermal Resistance

Symbol	Characteristics	Typ.	Max.	Units
R _{θJC}	Junction-to-case ③	—	1.72	°C/W
R _{θJA}	Junction-to-Ambient ④	—	62	°C/W

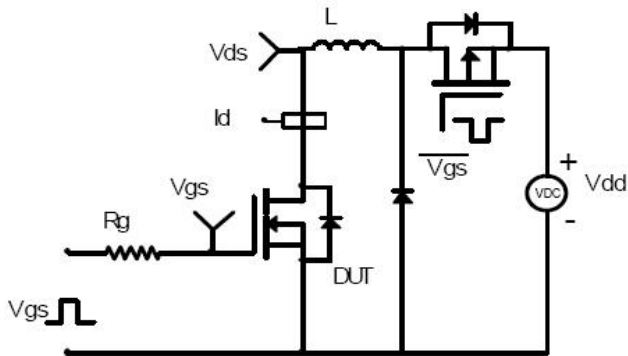
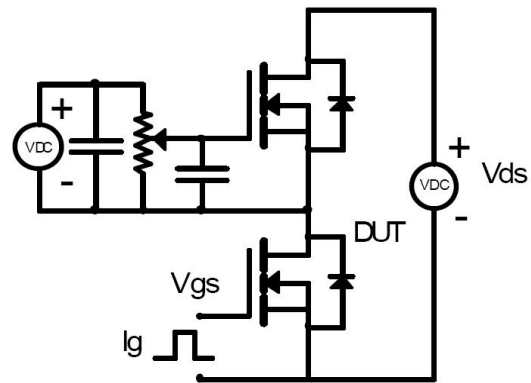
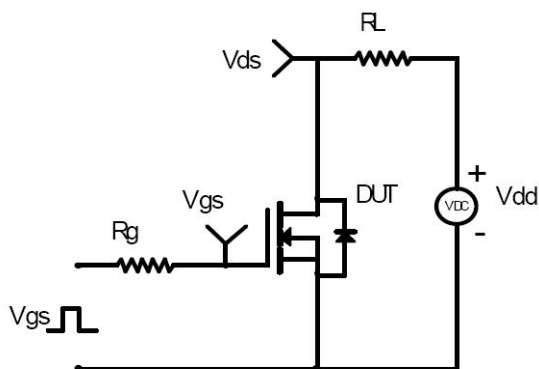
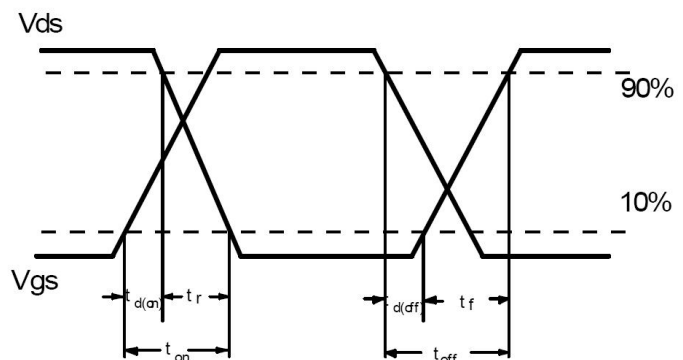
Electrical Characterizes @T_A=25°C unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source breakdown voltage	30	—	—	V	V _{GS} = 0V, I _D = 250μA
R _{DS(on)}	Static Drain-to-Source on-resistance	—	4.2	6	mΩ	V _{GS} =10V, I _D =30A
V _{GS(th)}	Gate threshold voltage	1	—	2.5	V	V _{DS} = V _{GS} , I _D =250μA
I _{DSS}	Drain-to-Source leakage current	—	—	1	μA	V _{DS} =30V, V _{GS} = 0V
I _{GSS}	Gate-to-Source forward leakage	—	—	100	nA	V _{GS} =20V
		—	—	-100		V _{GS} = -20V
Q _g	Total gate charge	—	21	—	nC	I _D = 30A, V _{DS} =15V, V _{GS} = 4.5V
Q _{gs}	Gate-to-Source charge	—	5	—		
Q _{gd}	Gate-to-Drain("Miller") charge	—	7	—		
t _{d(on)}	Turn-on delay time	—	22	—	ns	V _{GS} =10V, V _{DS} =15V, R _{GEN} =3Ω I _D = 30A
t _r	Rise time	—	18	—		
t _{d(off)}	Turn-Off delay time	—	50	—		
t _f	Fall time	—	26	—		
C _{iss}	Input capacitance	—	2048	—	pF	V _{GS} = 0V V _{DS} = 30V f = 1MHz
C _{oss}	Output capacitance	—	176	—		
C _{rss}	Reverse transfer capacitance	—	161	—		

Source-Drain Ratings and Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
I _S	Continuous Source Current (Body Diode)	—	—	100	A	MOSFET symbol showing the integral reverse p-n junction diode. 
I _{SM}	Pulsed Source Current (Body Diode)	—	—	400	A	
V _{SD}	Diode Forward Voltage	—	—	1.2	V	I _S =1A, V _{GS} =0V
t _{rr}	Reverse Recovery Time	—	17	—	ns	I _S =30A, di/dt=100A/us
Q _{rr}	Reverse Recovery Charge	—	9	—	nC	

Test Circuits and Waveforms

EAS Test Circuit:

Gate Charge Test Circuit:

Switching Time Test Circuit:

Switching Waveforms:


Notes:

- ① Calculated continuous current based on maximum allowable junction temperature.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ The power dissipation P_D is based on max. junction temperature, using junction-to-case thermal resistance.
- ④ The value of $R_{\theta JA}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$

Typical Electrical and Thermal Characteristics

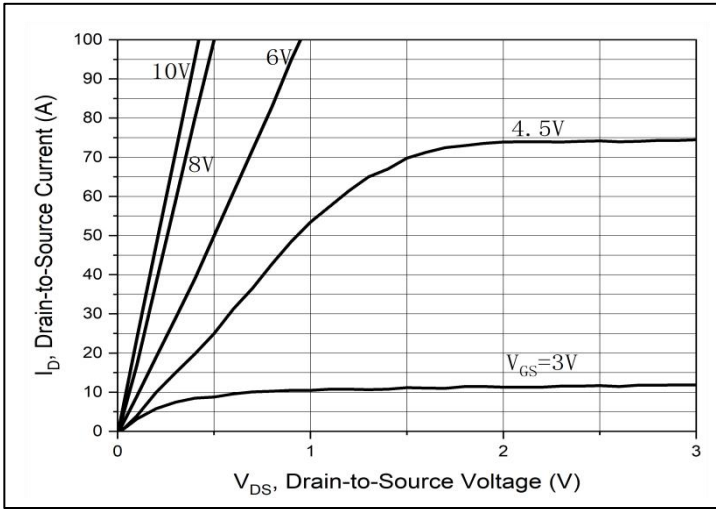


Figure1. Typical Output Characteristics

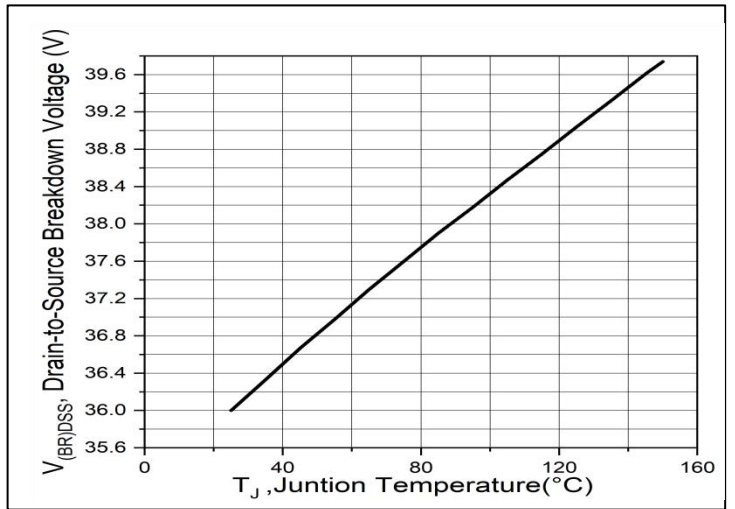


Figure2. Drain-to-Source Breakdown Voltage vs. Junction Temperature

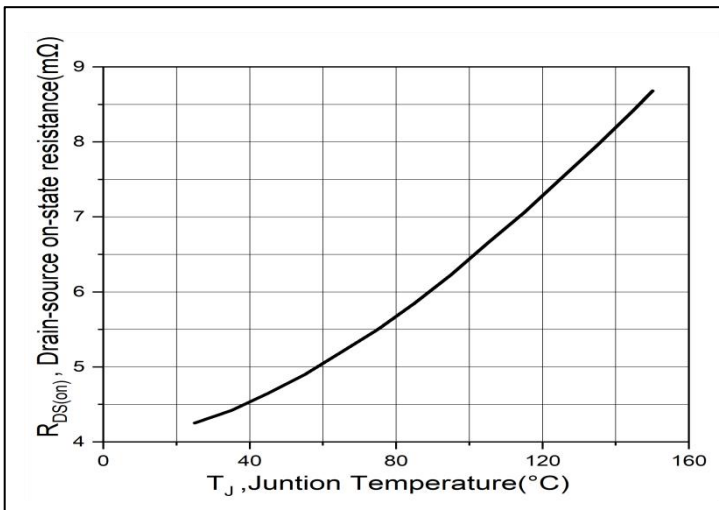


Figure3. R_DS(on) vs. Junction Temperature

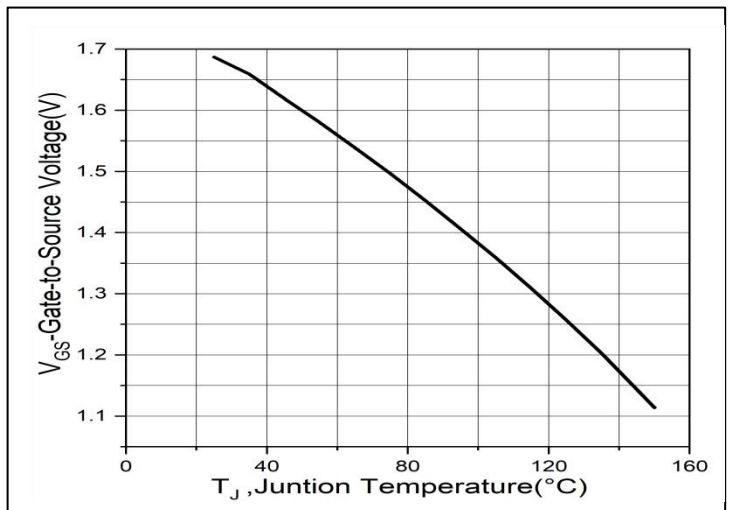


Figure4. V_{th} vs. Junction Temperature

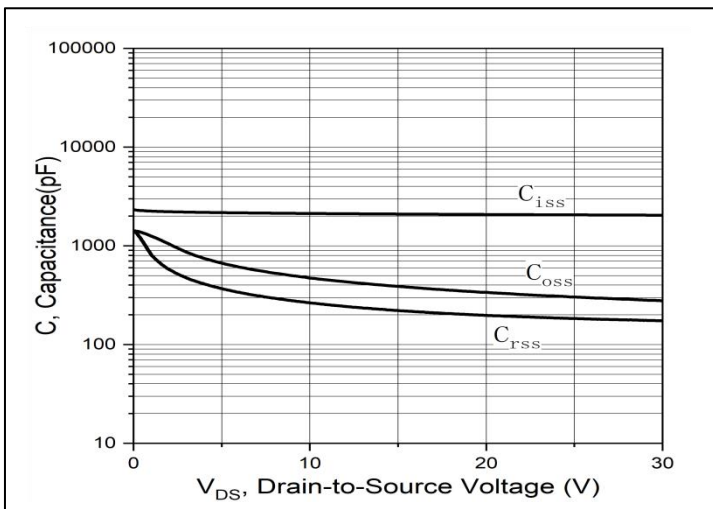


Figure5. Capacitance

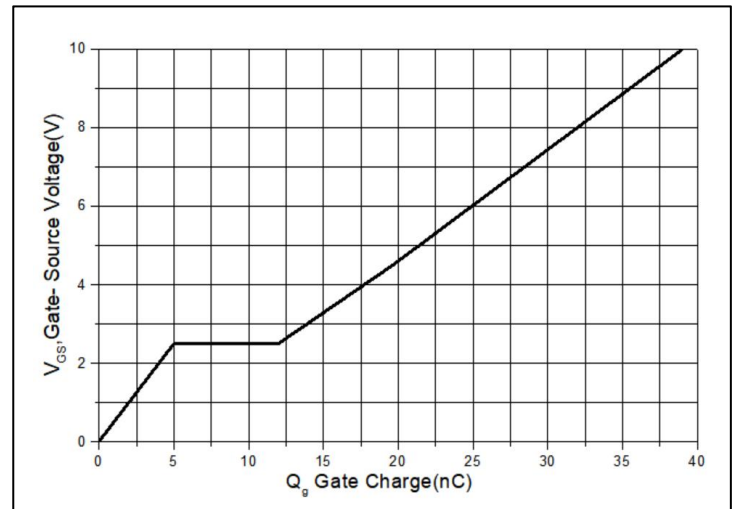
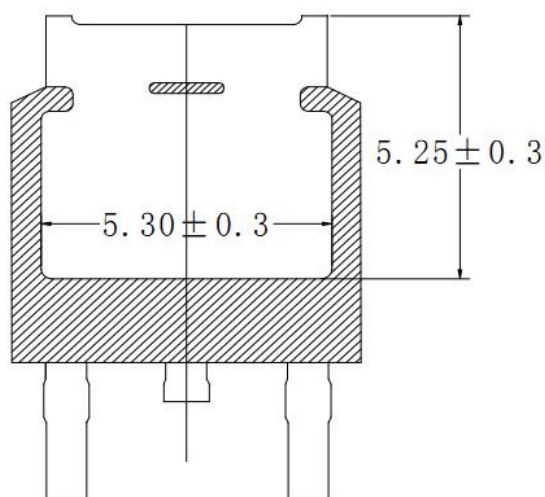
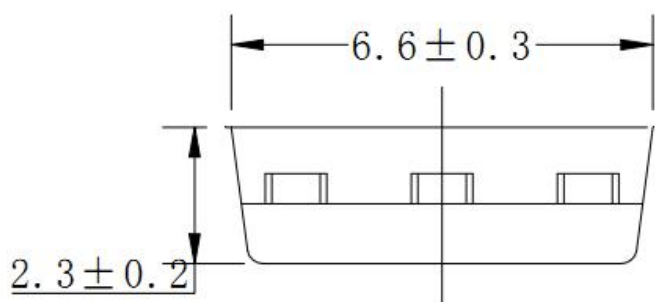
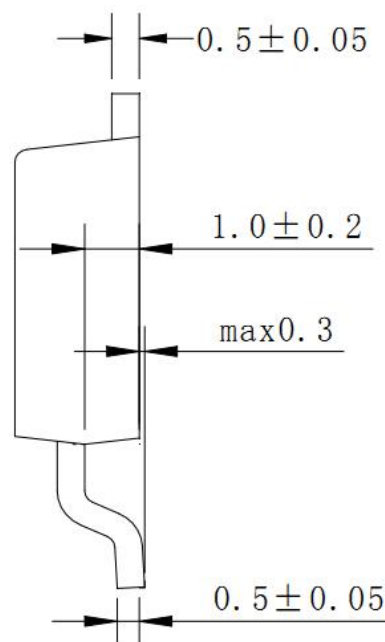
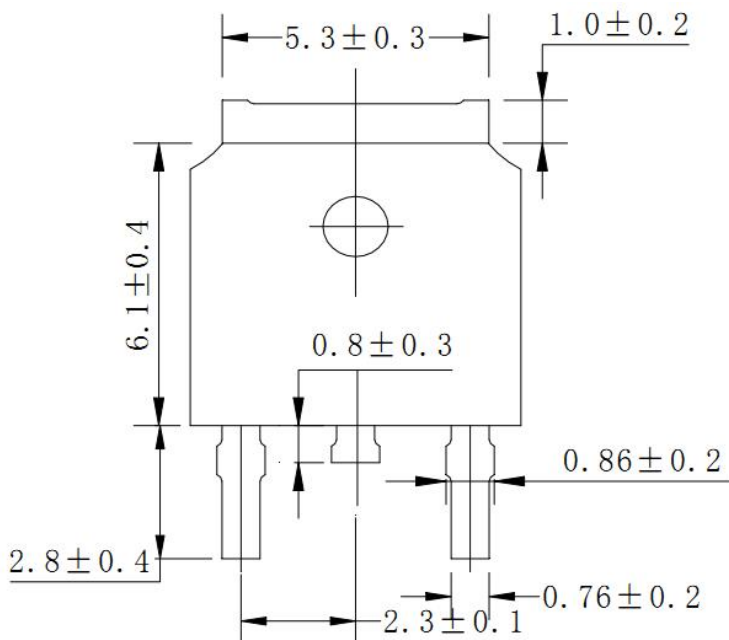
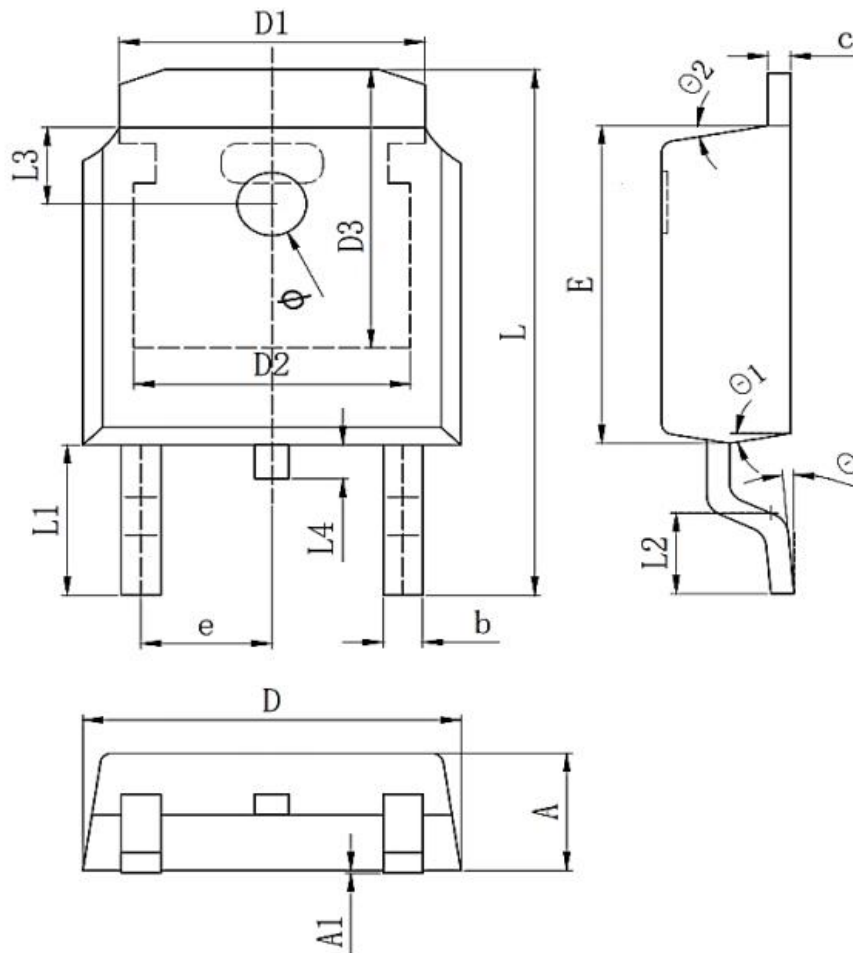


Figure6. Gate Charge

Mechanical Data:
Option1:

TO-252 Package Outline(Unit:mm)



Option2


Symbol	Dim in mm		
	Min	Typ	Max
A	2.1	2.3	2.5
A1	0	0.064	0.128
b	0.64	0.75	0.86
c	0.45	0.52	0.6
D	6.4	6.6	6.8
D1	5.33REF		
D2	4.83REF		
D3	5.25REF		
E	5.9	6.1	6.3
e	2.286TYP		
L	9.8	10.1	10.4
L1	2.888REF		
L2	1.4	1.5	1.7
L3	1.65REF		
L4	0.6	0.8	1
φ	1.1	1.2	1.3
θ	0°		10°
θ1	5°		10°
θ2	5°		10°

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